

<b>Notice of References Cited</b>	Application/Control No. 10/788,765		Applicant(s)/Patent Under Reexamination CHEN ET AL.	
	Examiner BRIAN E. MILLER		Art Unit 2627	Page 1 of 1

#### U.S. PATENT DOCUMENTS

*		Document Number Country Code-Number-Kind Code	Date MM-YYYY	Name	Classification
*	A	US-6,411,476 B1	06-2002	Lin et al.	360/324.11
*	B	US-2003/0011947 A1	01-2003	Saito et al.	360/324.11
*	C	US-2003/0030947 A1	02-2003	Ooshima, Masahiro	360/324.12
*	D	US-6,636,395 B1	10-2003	Terunuma, Koichi	360/324.11
*	E	US-6,668,443 B2	12-2003	Chien et al.	29/603.18
*	F	US-6,714,388 B2	03-2004	Hasegawa et al.	360/324.11
*	G	US-6,731,479 B2	05-2004	Ooshima et al.	360/324.12
*	H	US-6,760,200 B2	07-2004	Hasegawa, Naoya	360/324.12
*	I	US-6,833,981 B2	12-2004	Suwabe et al.	360/324.1
*	J	US-7,190,560 B2	03-2007	Gill, Hardayal Singh	360/324.11
	K	US-			
	L	US-			
	M	US-			

#### FOREIGN PATENT DOCUMENTS

*		Document Number Country Code-Number-Kind Code	Date MM-YYYY	Country	Name	Classification
	N					
	O					
	P					
	Q					
	R					
	S					
	T					

#### NON-PATENT DOCUMENTS

*		Include as applicable: Author, Title Date, Publisher, Edition or Volume, Pertinent Pages)
	U	
	V	
	W	
	X	

\*A copy of this reference is not being furnished with this Office action. (See MPEP § 707.05(a).)  
Dates in MM-YYYY format are publication dates. Classifications may be US or foreign.